

## 40-BIT EL-PANEL DRIVER

The  $\mu$ PD16332 is an EL panel row driver using a high breakdown voltage CMOS process. It consists of 40-bit bidirectional shift registers, and a high breakdown voltage CMOS driver block. The logic block operates on a 5-V power supply, designed to be connected directly to a microcontroller (CMOS level input). The driver block has a 250 V, 100 mA high breakdown voltage output, and both the logic block and driver block consist of CMOS, allowing operation with low power consumption.

### FEATURES

- High breakdown voltage CMOS structure
- High breakdown voltage, high current output (250 V, 100 mA MAX.)
- 40-bit directional shift registers on chip
- Data control by transfer clock (external)
- 80-pin plastic QFP (3-Direction Lead)
- Wide operating temperature range ( $T_A = -40$  to  $+85^\circ\text{C}$ )
- /PC pin allows polarity of all driver outputs to be inverted.

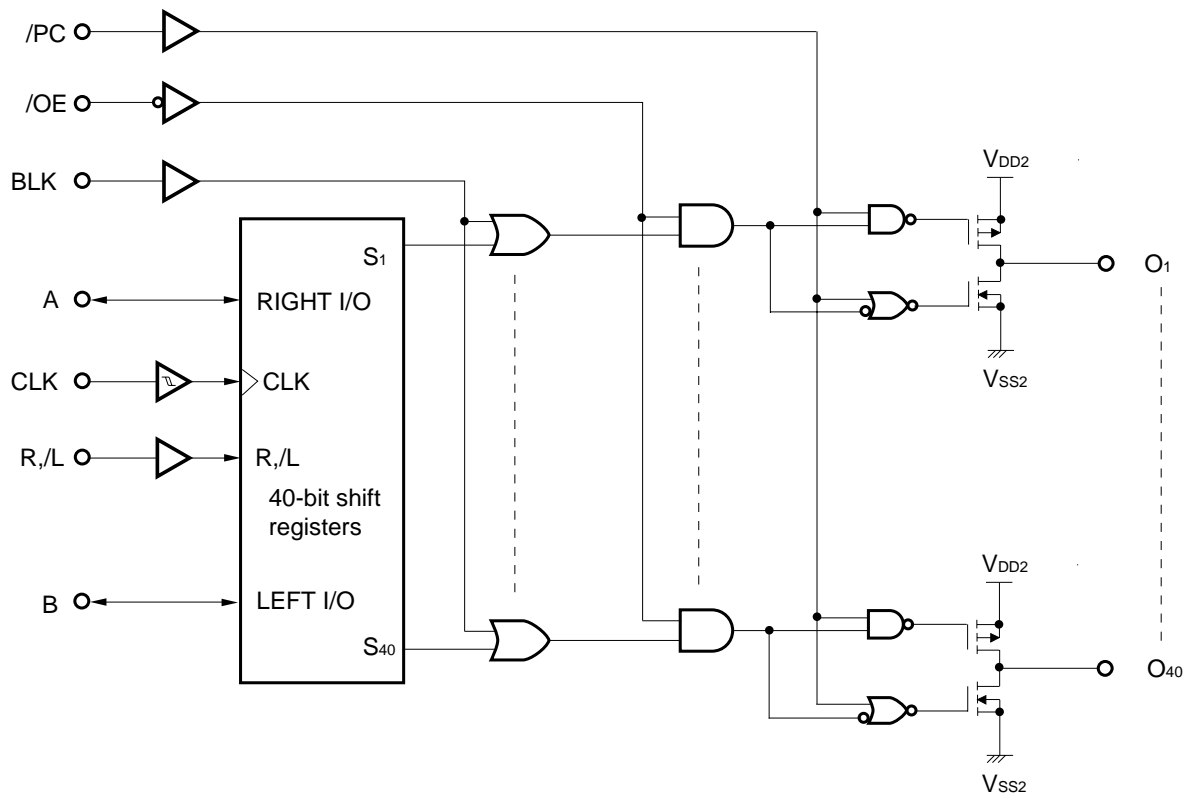
### ORDERING INFORMATION

Part Number	Package
$\mu$ PD16332GF-3L9	80-pin plastic QFP

**Remark** /xxx indicates active low signal.

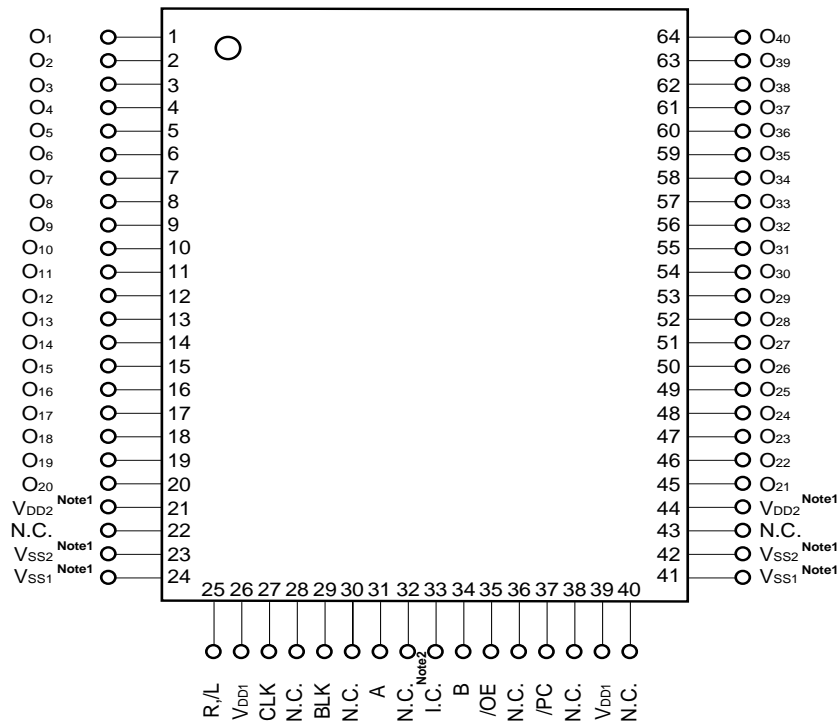
The information contained in this document is being issued in advance of the production cycle for the device. The parameters for the device may change before final production or NEC Corporation, at its own discretion, may withdraw the device prior to its production.

BLOCK DIAGRAM



**PIN CONFIGURATION (Top View)**

μPD16332GF-3L9



- Notes 1.** Be sure to use all pins V<sub>DD1</sub>, V<sub>DD2</sub>, V<sub>SS1</sub> and V<sub>SS2</sub>. Use V<sub>SS1</sub> and V<sub>SS2</sub> at the same potential.  
**2.** Pin 33 is connected to the lead frame internally, and therefore be sure to leave it open.

**Caution** Be sure to enter the power to V<sub>DD1</sub>, logic signal, and V<sub>DD2</sub>, in that order, and turn off the power in the reverse order.

**PIN CONFINGRATION**

Pin Symbol	Pin Name	Pin Number	Description
BLK	Blanking input	29	Please refer to the TRUTH TABLE 2.
/OE	Output enable input	35	Please refer to the TRUTH TABLE 2.
/PC	Polarity change input	37	/PC = L : Polarity of all outputs inverted
A	RIGHT data input	31	When R,/L = H, A: Input B: Output
B	LEFT data input	34	When R,/L = L, A: Output B: Input
CLK	Clock input	27	Shift is executed on a rising edge.
R,/L	Shift control input	25	H: Right shift mode A → O <sub>1</sub> ... O <sub>40</sub> → B L: Left shift mode B → O <sub>40</sub> ... O <sub>1</sub> → A
O <sub>1</sub> to O <sub>40</sub>	High breakdown voltage output	1 to 20, 45 to 64	250 V, 100 mA MAX.
V <sub>DD1</sub>	Logic block power supply	26, 39	5 V ± 10 %
V <sub>DD2</sub>	Driver block power supply	21, 44	30 to 240 V
V <sub>SS1</sub>	Logic ground	24, 41	Connected to system GND
V <sub>SS2</sub>	Driver ground	23, 42	Connected to system GND
I.C.	Internal-connection	33	Connected to the lead frame internally Be sure to leave it open.
N.C.	Free pins	22, 28, 30, 32, 36, 38, 40, 43	Non-connection

**TRUTH TABLE 1 (SHIFT REGISTER BLOCK)**

Input		Output		Shift register
R,/L	CLK	A	B	
H	↑	S <sub>1</sub> Input	S <sub>40</sub> Output	Execution of right shift
H	H or L			Retained
L	↑	S <sub>1</sub> Output	S <sub>40</sub> Input	Execution of left shift
L	H or L			Retained

**TRUTH TABLE 2 (DRIVER BLOCK)**

DATA	BLK	/OE	/PC	On	Reference
×	H	L	H	H	All driver outputs are H.
×	H	L	L	L	All driver outputs are L.
×	×	H	×	Z	All driver outputs are Z.
L	L	L	×	Z	
H	L	L	H	H	
H	L	L	L	L	

**Remark** H : High Level , L : Low Level , ×: H or L , Z : High Impedance ,  
DATA : Contence of the Shift Register

**ELECTRICAL CHARACTERISTICS**

**ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = +25 °C, V<sub>SS1</sub> = V<sub>SS2</sub> = 0 V)**

Item	Symbol	Rating	Unit
Logic supply voltage	V <sub>DD1</sub>	-0.5 to +6.0	V
Driver supply voltage	V <sub>DD2</sub>	-0.5 to +250	V
Logic input voltage	V <sub>I1</sub>	-0.5 to V <sub>DD1</sub> + 0.5	V
Logic output voltage	V <sub>O1</sub>	-0.5 to V <sub>DD1</sub> + 0.5	V
Driver output voltage	V <sub>O2</sub>	-0.5 to V <sub>DD2</sub> + 0.5	V
Driver output current	I <sub>O2</sub>	±100	mA
Power dissipation	P <sub>D</sub>	1000 <sup>Note</sup>	mW
Operating ambient temperature	T <sub>A</sub>	-40 to +85	°C
Storage temperature	T <sub>stg.</sub>	-65 to +150	°C

**Note** When T<sub>A</sub> ≥ +25 °C, load should be alleviated at a rate of -8.0 mW/°C.

**Caution** If the absolute maximum rating of even one of the above parameters is exceeded even momentarily, the quality of the product may be degraded. Absolute maximum ratings, therefore, specify the values exceeding which the product may be physically damaged. Be sure to use the product within the range of the absolute maximum ratings.

**RECOMMENDED OPERATING RANGE (T<sub>A</sub> = -40 to +85 °C, V<sub>SS1</sub> = V<sub>SS2</sub> = 0 V)**

Item	Symbol	MIN.	TYP.	MAX.	Unit
Logic supply voltage	V <sub>DD1</sub>	4.5	5.0	5.5	V
Driver supply voltage	V <sub>DD2</sub>	30		240	V
Input voltage high	V <sub>IH</sub>	0.7·V <sub>DD1</sub>		V <sub>DD1</sub>	V
Input voltage low	V <sub>IL</sub>	0		0.2·V <sub>DD1</sub>	V
Driver output current	I <sub>OH</sub>			-70	mA
	I <sub>OL</sub>			+70	mA

**ELECTRICAL CHARACTERISTICS**

**(T<sub>A</sub> = + 25 °C, V<sub>DD1</sub> = 4.5 to 5.5 V, V<sub>DD2</sub> = 240 V, V<sub>SS1</sub> = V<sub>SS2</sub> = 0 V)**

Item	Symbol	Condition	MIN.	TYP.	MAX.	Unit
High level output voltage	V <sub>OH1</sub>	Logic, I <sub>OH</sub> = -1.0 mA	0.9·V <sub>DD1</sub>		V <sub>DD1</sub>	V
Low level output voltage	V <sub>OL1</sub>	Logic, I <sub>OL</sub> = 1.0 mA	0		0.1·V <sub>DD1</sub>	V
High level output voltage	V <sub>OH21</sub>	O <sub>1</sub> to O <sub>40</sub> , I <sub>OH</sub> = -10 mA	220			V
	V <sub>OH22</sub>	O <sub>1</sub> to O <sub>40</sub> , I <sub>OH</sub> = -70 mA	190			V
Low level output voltage	V <sub>OL21</sub>	O <sub>1</sub> to O <sub>40</sub> , I <sub>OL</sub> = 10 mA			20	V
	V <sub>OL22</sub>	O <sub>1</sub> to O <sub>40</sub> , I <sub>OL</sub> = 70 mA			35	V
3-state output current	I <sub>TL</sub>	V <sub>O2</sub> = V <sub>DD2</sub> or V <sub>SS2</sub>			±10.0	μA
Input leakage current	I <sub>IL</sub>	V <sub>I</sub> = V <sub>DD1</sub> or V <sub>SS1</sub>			±1.0	μA
High level input voltage	V <sub>IH</sub>		0.7·V <sub>DD1</sub>			V
Low level input voltage	V <sub>IL</sub>				0.2·V <sub>DD1</sub>	V
Static consumption current	I <sub>DD11</sub>	Logic, T <sub>A</sub> = +25 °C			100	μA
	I <sub>DD12</sub>	Logic, T <sub>A</sub> = -40 to +85 °C			1000	μA
	I <sub>DD21</sub>	Driver, T <sub>A</sub> = +25 °C			100	μA
	I <sub>DD22</sub>	Driver, T <sub>A</sub> = -40 to +85 °C			1000	μA

**SWITCHING CHARACTERISTICS** ( $T_A = +25\text{ }^\circ\text{C}$ ,  $V_{DD1} = 4.5\text{ to }5.5\text{ V}$ ,  $V_{DD2} = 240\text{ V}$ , Logic  $C_L = 15\text{ pF}$ , Driver  $C_L = 330\text{ pF}$ , Driver  $R_L = 10\text{ k}\Omega$ )

Item	Symbol	Condition	MIN.	TYP.	MAX.	Unit	
Transmission delay time	t <sub>PHL1</sub>	CLK → A/B			100	ns	
	t <sub>PLH1</sub>				100	ns	
	t <sub>PZH2</sub>	CLK → O <sub>1</sub> to O <sub>40</sub>			500	ns	
	t <sub>PZL2</sub>				500	ns	
	t <sub>PHZ2</sub>				1.0	μs	
	t <sub>PLZ2</sub>				1.0	μs	
	t <sub>PHL3</sub>		/PC → O <sub>1</sub> to O <sub>40</sub>			1.0	μs
	t <sub>PLH3</sub>					1.0	μs
	t <sub>PZH4</sub>	/OE → O <sub>1</sub> to O <sub>40</sub>			500	ns	
	t <sub>PZL4</sub>				500	ns	
	t <sub>PHZ4</sub>				1.0	μs	
	t <sub>PLZ4</sub>				1.0	μs	
	t <sub>PZH5</sub>	BLK → O <sub>1</sub> to O <sub>40</sub>			500	ns	
	t <sub>PZL5</sub>				500	ns	
	t <sub>PHZ5</sub>				1.0	μs	
t <sub>PLZ5</sub>				1.0	μs		
Rise time	t <sub>TZH</sub>	O <sub>1</sub> to O <sub>40</sub>			2.0	μs	
	t <sub>TLH</sub>				2.0	μs	
	t <sub>TLZ</sub>				15	μs	
Fall time	t <sub>TZL</sub>	O <sub>1</sub> to O <sub>40</sub>			2.0	μs	
	t <sub>THL</sub>				2.0	μs	
	t <sub>THZ</sub>				15	μs	
Maximum clock frequency	f <sub>max.</sub>	Data fetch, Duty = 50 %	10			MHz	
		With cascading, Duty = 50 %	6.6			MHz	
Input capacitance	C <sub>I</sub>				15	pF	

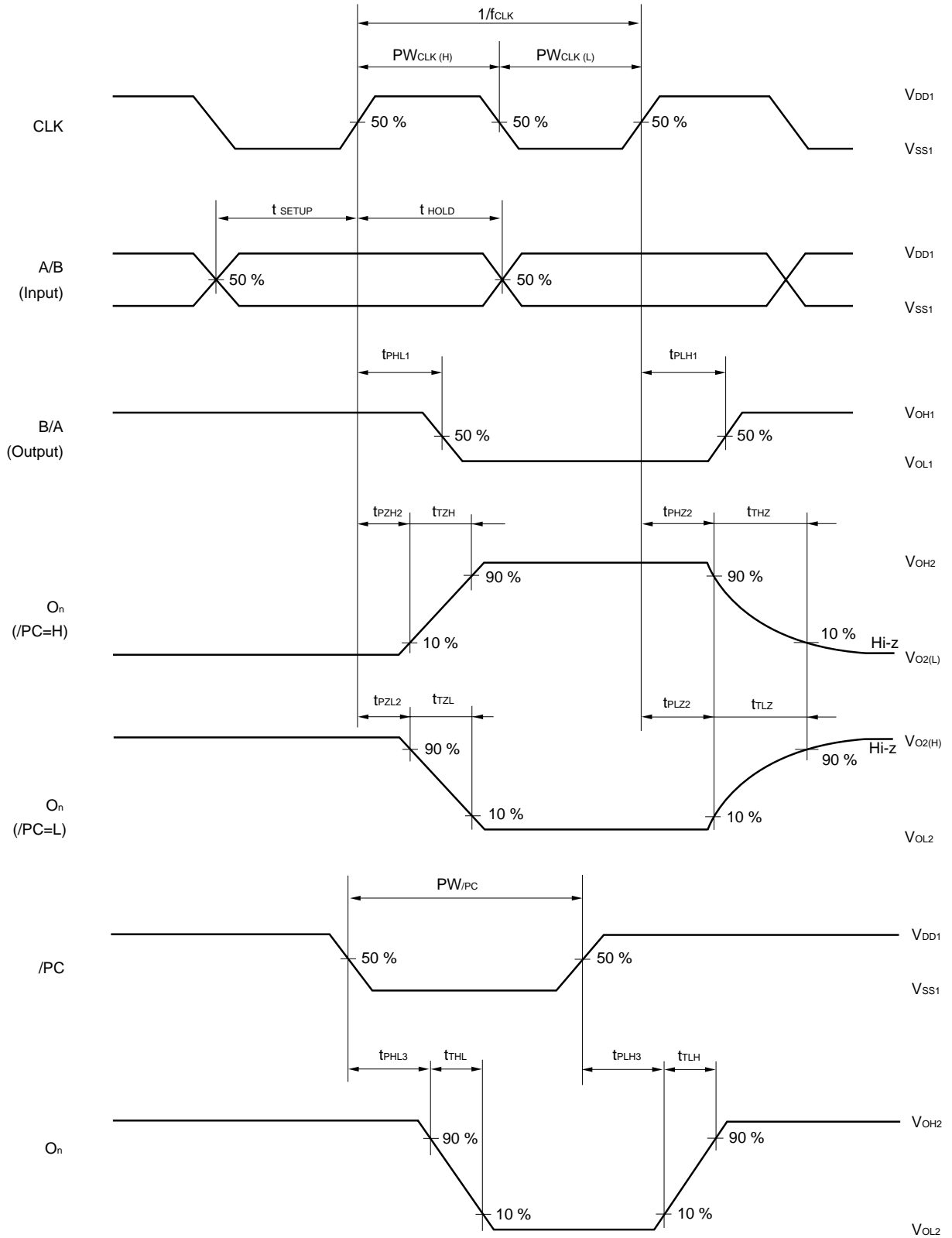
**TIMING REQUIREMENTS** ( $T_A = -40\text{ to }+85\text{ }^\circ\text{C}$ ,  $V_{DD1} = 4.5\text{ to }5.5\text{ V}$ ,  $V_{SS1} = V_{SS2} = 0\text{ V}$ )

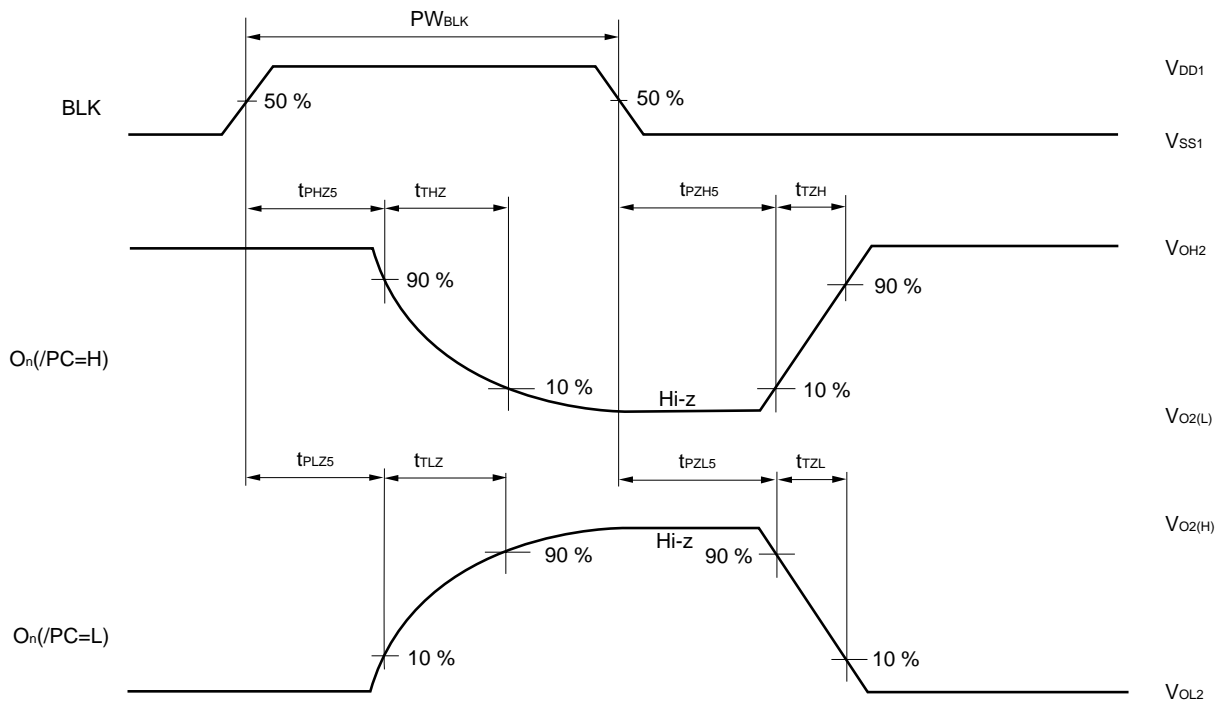
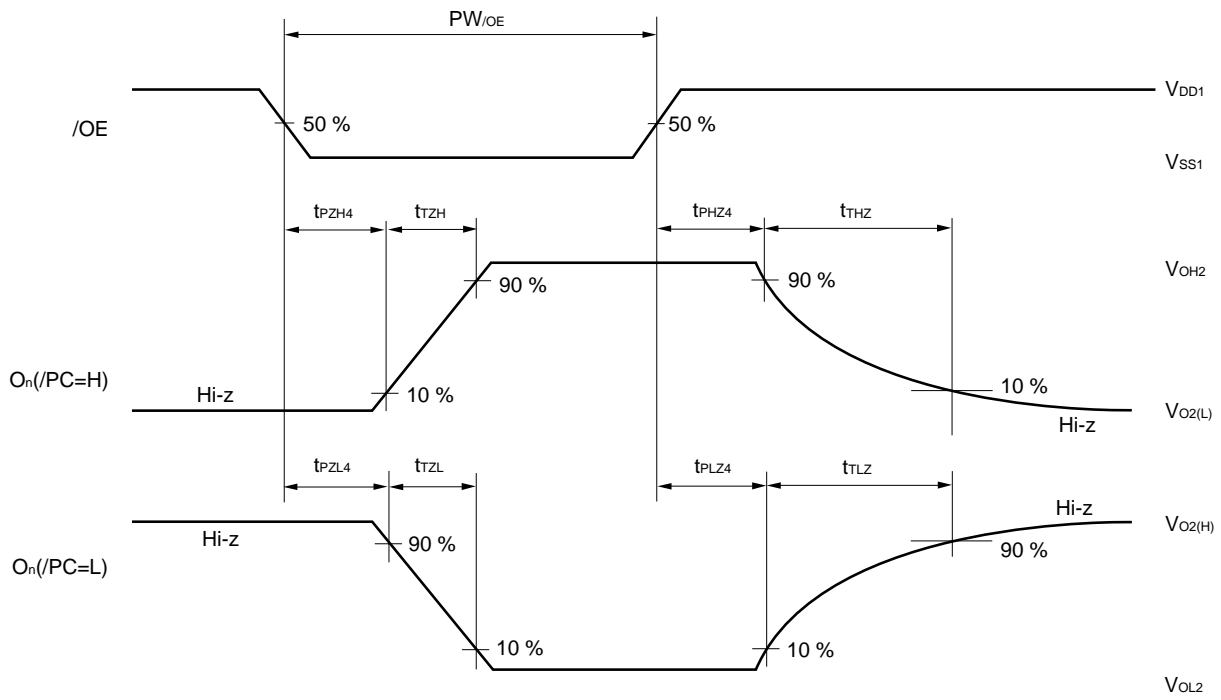
Item	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Clock pulse width	PW <sub>CLK</sub>		50			ns
Blank pulse width	PW <sub>BLK</sub>		3			μs
/PC pulse width	PW <sub>/PC</sub>		3			μs
Enable pulse width	PW <sub>/OE</sub>		3			μs
Data setup time	t <sub>SETUUP</sub>		50			ns
Data hold time	t <sub>HOLD</sub>		50			ns

SWITCHING CHARACTERISTIC WAVEFORM (R,L = H)

( ) : For Left Shift

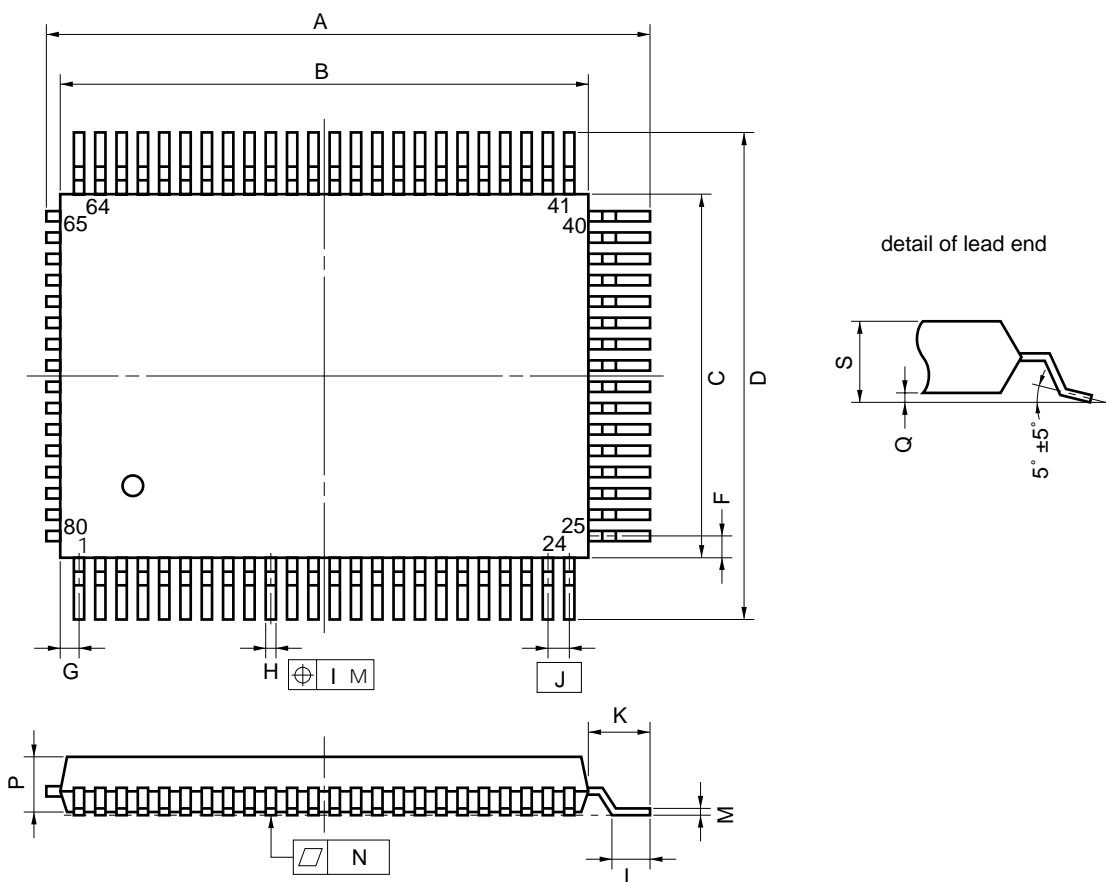
$V_{IH} = V_{IL} = 0.5V_{DD1}$





PACKAGE DRAWING

80 PIN PLASTIC QFP (THREE DIRECTIONS) (14X20)



NOTE

Each lead centerline is located within 0.15 mm (0.006 inch) of its true position (T.P.) at maximum material condition.

P80GF-80-3L9-1

ITEM	MILLIMETERS	INCHES
A	22.3±0.4	0.878±0.016
B	20.0±0.2	0.795 <sup>+0.009</sup> <sub>-0.008</sub>
C	14.0±0.2	0.551 <sup>+0.009</sup> <sub>-0.008</sub>
D	17.6±0.4	0.693±0.016
F	1.0	0.039
G	0.8	0.031
H	0.35±0.10	0.014 <sup>+0.004</sup> <sub>-0.005</sub>
I	0.15	0.006
J	0.8 (T.P.)	0.031 (T.P.)
K	1.8±0.2	0.071 <sup>+0.008</sup> <sub>-0.009</sub>
L	0.8±0.2	0.031 <sup>+0.009</sup> <sub>-0.008</sub>
M	0.15 <sup>+0.10</sup> <sub>-0.05</sub>	0.006 <sup>+0.004</sup> <sub>-0.003</sub>
N	0.15	0.006
P	2.7	0.106
Q	0.1±0.1	0.004±0.004
S	3.0 MAX.	0.119 MAX.

**RECOMMENDED SOLDERING CONDITIONS**

The following conditions must be met for soldering conditions of the μPD16332.

For more details, refer to the **Semiconductor Device Mounting Technology Manual(C10535E)**.

Please consult with our sales offices in case other soldering process is used, or in case the soldering is done under different conditions.

**Type of Surface Mount Device**

**μPD16332GF-3L9 : 80-pin plastic QFP**

Soldering Method	Soldering Conditions	Recommended Condition Symbol
Infrared reflow	T.B.D.	—
VPS	T.B.D.	—
Pin partial heating	Pin partial temperature: 300°C MAX., Duration: 3 sec. MAX., Time limit: None <sup>Note</sup>	

**Note** Exposure limit before soldering after dry-pack package is opened.

Storage conditions : 25°C and relative humidity at 65% or less.

**Caution** Do you apply more than one soldering method t any one time, except for the partial heating method.

## NOTES FOR CMOS DEVICES

### ① PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

**Note:** Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

### ② HANDLING OF UNUSED INPUT PINS FOR CMOS

**Note:** No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to  $V_{DD}$  or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

### ③ STATUS BEFORE INITIALIZATION OF MOS DEVICES

**Note:** Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

## References

Semiconductor Device Mounting Technology Manual(C10535E)  
Quality Grade on NEC Semiconductor Devices (C11531E)

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While NEC Corporation has been making continuous effort to enhance the reliability of its semiconductor devices, the possibility of defects cannot be eliminated entirely. To minimize risks of damage or injury to persons or property arising from a defect in an NEC semiconductor device, customers must incorporate sufficient safety measures in its design, such as redundancy, fire-containment, and anti-failure features.

NEC devices are classified into the following three quality grades:

"Standard", "Special", and "Specific". The Specific quality grade applies only to devices developed based on a customer designated "quality assurance program" for a specific application. The recommended applications of a device depend on its quality grade, as indicated below. Customers must check the quality grade of each device before using it in a particular application.

Standard: Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots

Special: Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)

Specific: Aircrafts, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems or medical equipment for life support, etc.

The quality grade of NEC devices is "Standard" unless otherwise specified in NEC's Data Sheets or Data Books. If customers intend to use NEC devices for applications other than those specified for Standard quality grade, they should contact an NEC sales representative in advance.

Anti-radioactive design is not implemented in this product.